

Laboratoire Léon Brillouin



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New applications of very-high resolution inelastic X-ray scattering.

Mardi 22 janvier 2008 à 14h 30

Salle de conférence 15 – Bâtiment 563

In the last two decades the inelastic X-ray scattering (IXS) in the meV energy range has become a powerful spectroscopic tool complementary to the well-established inelastic neutron scattering (INS). At the European Synchrotron Radiation Facility (ESRF), there are currently two three-axis spectrometers (ID16 and ID28 beamlines) working with close-to-backscattering geometry, dedicated to phonon spectroscopy. It is worth noting that with respect to INS, the amount of material needed is 3-5 orders less, and anomalous absorption (like for B, Cd, Gd...) or anomalously high cross-sections (H) are not present. So, the IXS can be applied to very wide class of materials, including the experiments under the extreme conditions. Some applied aspects will be presented, including phonon density of states probed by the IXS and elasticity of highly anisotropic systems.

Formalités d'entrée : Contacter le Secrétariat pour votre autorisation d'entrer sur le Centre de Saclay :

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Le délai minimum est de 24 heures pour les ressortissants des pays de l'Union Européenne et de 5 jours pour les autres.

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